

# Cut Big Problems Down to Size



## With Innovative AFM Solutions

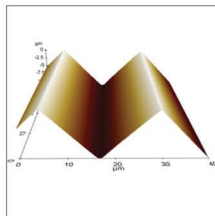
Intrinsic bowing in atomic force microscopy messing up your flat sample images? Having difficulty measuring overhang structures? Can't get the spatial and thermal resolution you need to measure heat dispersion? Major problems, indeed.

### No Crosstalk. No Problems.

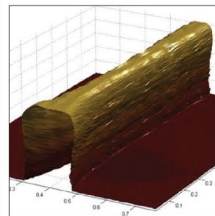
While some AFMs still use 1980's technology, we've leveraged innovations in hardware, software and probes to deliver scans with astounding clarity and accuracy. And our XE Family™ of AFMs and new NSOM Systems repeat those results sample after sample.

### A Decade of "Can Do."

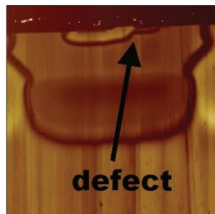
Park Systems may be a new name. But we're not a new company. In fact, we've been around since the AFM was invented, winning one industry award after another. Call us at 408-986-1110 and we'll show you *Excellence in Nanometrology*.



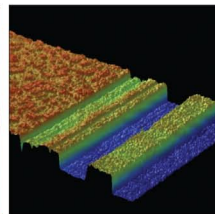
Angle Measurements



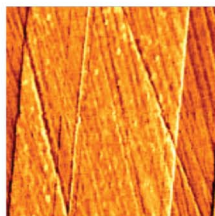
Photoresist Overhang



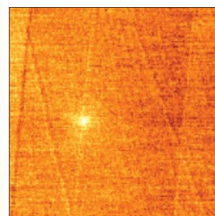
Dopant Imaging



Hard Disk Slider



Disk Head Imaging ( $2\ \mu\text{m} \times 2\ \mu\text{m}$ )



Topographical Image Thermal Image



**Park**  
**SYSTEMS**

[www.parkAFM.com](http://www.parkAFM.com)